

U.S. Department of Commerce, Patent and Trademark INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Atty. Docket No. SNDK.352US0	Application No. 10/799,060			
(Use several sheets if necessary)		Applicant(s) Jeffrey Lurze et al.				
JAN 24 2005		Filing Date March 12, 2004	Group 2818			
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

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(Form PTO-1449)		Jeffrey W. LUTZE et al.	6740
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